# RENESAS

# HAF1001 Silicon P Channel MOS FET Series Power Switching

REJ03G1132-0400 (Previous: ADE-208-583A) Rev.4.00 Apr 27, 2006

### Description

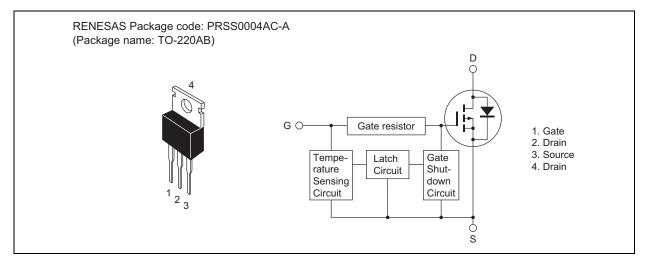
This FET has the over temperature shut-down capability sensing to the junction temperature.

This FET has the built-in over temperature shut-down circuit in the gate area. And this circuit operation to shut-down the gate voltage in case of high junction temperature like applying over power consumption, over current etc.

### Features

- Logic level operation (-4 to -6 V Gate drive)
- High endurance capability against to the short circuit
- Built-in the over temperature shut-down circuit
- Latch type shut-down operation (Need 0 voltage recovery)

### Outline





### **Absolute Maximum Ratings**

			$(Ta = 25^{\circ}C)$
Item	Symbol	Value	Unit
Drain to source voltage	V <sub>DSS</sub>	-60	V
Gate to source voltage	V <sub>GSS</sub>	-16	V
	V <sub>GSS</sub>	3	V
Drain current	Ι <sub>D</sub>	-15	А
Drain peak current	I <sub>D (pulse)</sub> Note 1	-30	А
Body-drain diode reverse drain current	I <sub>DR</sub>	-15	А
Channel dissipation	Pch Note 2	50	W
Channel temperature	Tch	150	٥C
Storage temperature	Tstg	-55 to +150	٥°

Notes: 1.  $PW \le 10 \ \mu s$ , duty cycle  $\le 1\%$ 

2. Value at Tc =  $25^{\circ}C$ 

## **Typical Operation Characteristics**

Item	Symbol	Min	Тур	Max	Unit	Test Conditions
Input voltage	V <sub>IH</sub>	-3.5		—	V	
	V <sub>IL</sub>	—	_	-1.2	V	
Input current	I <sub>IH1</sub>	—	_	-100	μA	$Vi = -8 V, V_{DS} = 0$
(Gate non shut down)	I <sub>IH2</sub>	—	_	-50	μA	$Vi = -3.5 V, V_{DS} = 0$
	l <sub>IL</sub>	—	_	-1	μA	$Vi = -1.2 V, V_{DS} = 0$
Input current	I <sub>IH (sd) 1</sub>	—	-0.8	—	mA	$Vi = -8 V, V_{DS} = 0$
(Gate shut down)	I <sub>IH (sd) 2</sub>	—	-0.35	—	mA	$Vi = -3.5 V, V_{DS} = 0$
Shut down temperature	Tsd	—	175		°C	Channel temperature
Gate operation voltage	V <sub>OP</sub>	-3.5		-13	V	



### **Electrical Characteristics**

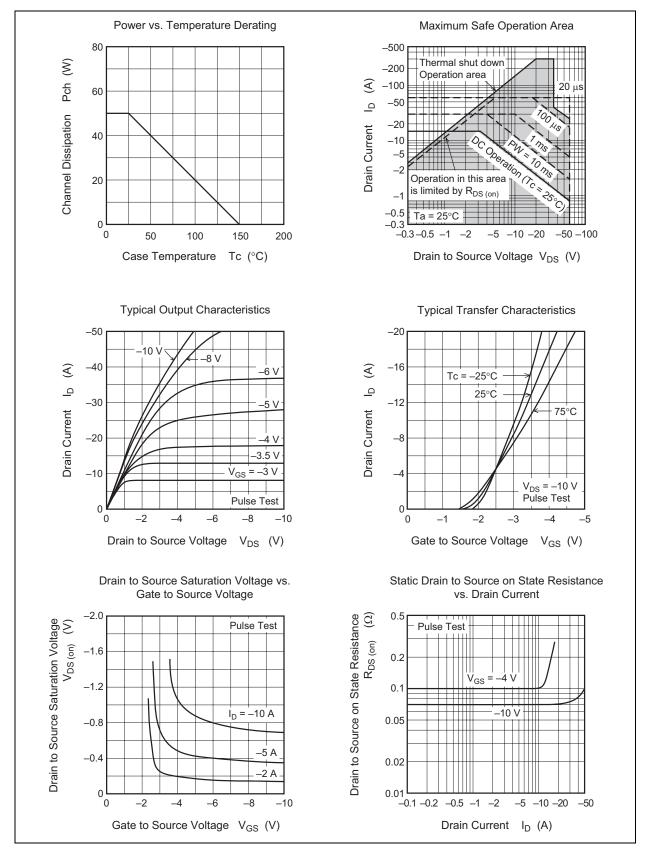
						$(Ta = 25^{\circ}C)$
Item	Symbol	Min	Тур	Max	Unit	Test Conditions
Drain current	I <sub>D1</sub>	-7	—	—	А	$V_{GS} = -3.5 \text{ V},  V_{DS} = -2 \text{ V}$
	I <sub>D2</sub>	—	—	-10	mA	$V_{GS} = -1.2 \text{ V}, V_{DS} = -2 \text{ V}$
Drain to source breakdown voltage	V (BR) DSS	-60		—	V	$I_D = -10 \text{ mA}, V_{GS} = 0$
Gate to source breakdown voltage	V (BR) GSS	-16		—	V	$I_{G} = -100 \ \mu A, \ V_{DS} = 0$
	V (BR) GSS	3	—	—	V	$I_G = 100 \ \mu A, \ V_{DS} = 0$
Gate to source leak current	I <sub>GSS1</sub>	—	—	-100	μΑ	$V_{GS} = -8 \text{ V},  V_{DS} = 0$
	I <sub>GSS2</sub>	—	—	-50	μΑ	$V_{GS} = -3.5 \text{ V},  V_{DS} = 0$
	I <sub>GSS3</sub>	—	—	-1	μΑ	$V_{GS} = -1.2 V, V_{DS} = 0$
	I <sub>GSS4</sub>	—	—	100	μΑ	$V_{GS} = 2.4 V, V_{DS} = 0$
Input current (shut down)	I <sub>GS (op) 1</sub>	—	-0.8	—	mA	$V_{GS} = -8 \text{ V},  V_{DS} = 0$
	I <sub>GS (op) 2</sub>	—	-0.35	—	mA	$V_{GS} = -3.5 \text{ V}, V_{DS} = 0$
Zero gate voltage drain current	I <sub>DSS</sub>	—	—	-250	μΑ	$V_{DS} = -50 \text{ V}, \text{ V}_{GS} = 0$
Gate to source cutoff voltage	V <sub>GS (off)</sub>	-1.1	—	-2.25	V	$I_D = -1 \text{ mA}, V_{DS} = -10 \text{ V}$
Static drain to source on state resistance	R <sub>DS (on)</sub>	—	100	130	mΩ	$I_D = -7.5 \text{ A}, V_{GS} = -4 \text{ V}^{Note 3}$
	R <sub>DS (on)</sub>	—	70	90	mΩ	$I_D = -7.5 \text{ A}, V_{GS} = -10 \text{ V}^{Note 3}$
Forward transfer admittance	y <sub>fs</sub>	5	10	—	S	$I_D = -7.5 \text{ A}, V_{DS} = -10 \text{ V}^{Note 3}$
Output capacitance	Coss	—	610	—	pF	$V_{DS} = -10 V, V_{GS} = 0$
						f = 1 MHz
Turn-on delay time	t <sub>d (on)</sub>		7.5	—	μs	I <sub>D</sub> = -7.5 A
Rise time	tr		36	—	μs	$V_{GS} = -5 V$
Turn-off delay time	t <sub>d (off)</sub>	—	32	—	μs	$R_L = 4 \Omega$
Fall time	t <sub>f</sub>	—	29	—	μs	
Body-drain diode forward voltage	V <sub>DF</sub>	—	-1.0	—	V	$I_F = -15 \text{ A}, V_{GS} = 0$
Body-drain diode reverse recovery time	t <sub>rr</sub>	—	200	—	ns	$I_F = -15 \text{ A}, V_{GS} = 0$
						di <sub>F</sub> /dt = 50 A/µs
Over load shut down operation time Note4	t <sub>os1</sub>		3.7	—	ms	$V_{GS} = -5 V, V_{DD} = -12 V$
	t <sub>os2</sub>		1	—	ms	$V_{GS} = -5 \text{ V},  V_{DD} = -24 \text{ V}$

Notes: 3. Pulse test

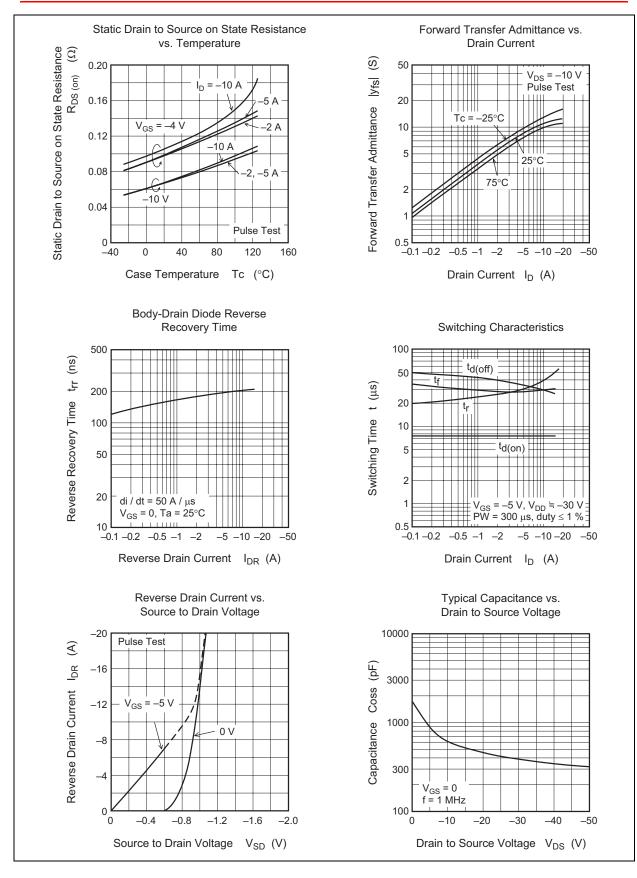
4. Include the time shift based on increasing of channel temperature when operate under over load condition.



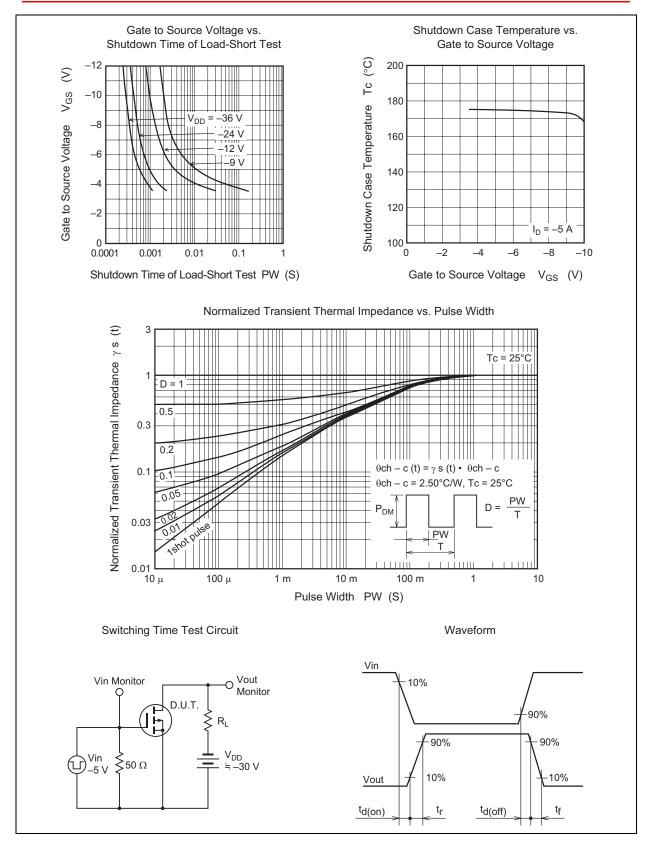
### **Main Characteristics**





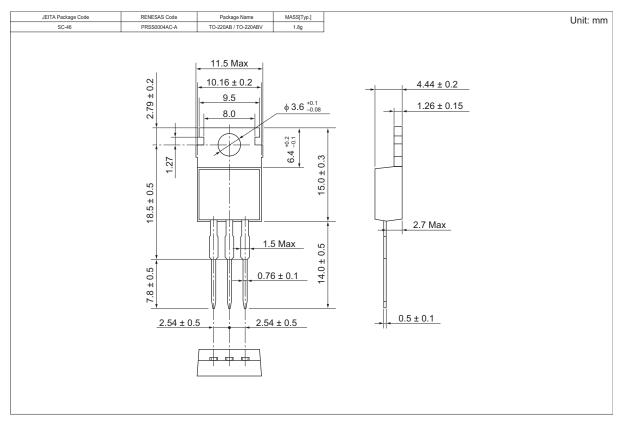








### **Package Dimensions**



### **Ordering Information**

Part Name	Quantity	Shipping Container
HAF1001-90	Max: 50 pcs/sack	Sack

Note: For some grades, production may be terminated. Please contact the Renesas sales office to check the state of production before ordering the product.



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